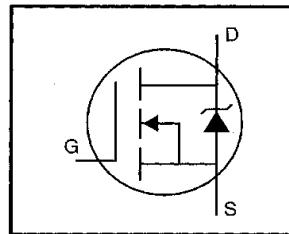


# IRF624PbF

## HEXFET® Power MOSFET

- Dynamic dv/dt Rating
- Repetitive Avalanche Rated
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Lead-Free

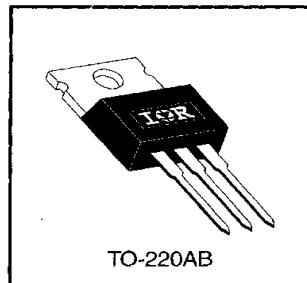


$V_{DSS} = 250V$
$R_{DS(on)} = 1.1\Omega$
$I_D = 4.4A$

### Description

Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.



### Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10 V$	4.4	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10 V$	2.8	
$I_{DM}$	Pulsed Drain Current ①	14	
$P_D @ T_C = 25^\circ C$	Power Dissipation	50	W
	Linear Derating Factor	0.40	W/°C
$V_{GS}$	Gate-to-Source Voltage	±20	V
$E_{AS}$	Single Pulse Avalanche Energy ②	100	mJ
$I_{AR}$	Avalanche Current ①	4.4	A
$E_{AR}$	Repetitive Avalanche Energy ①	5.0	mJ
$dv/dt$	Peak Diode Recovery dv/dt ③	4.8	V/ns
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting Torque, 6-32 or M3 screw	10 lbf-in (1.1 N·m)	

### Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units
$R_{JC}$	Junction-to-Case	—	—	2.5	°C/W
$R_{CS}$	Case-to-Sink, Flat, Greased Surface	—	0.50	—	
$R_{JA}$	Junction-to-Ambient	—	—	62	

# IRF624PbF

International  
Rectifier

## Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

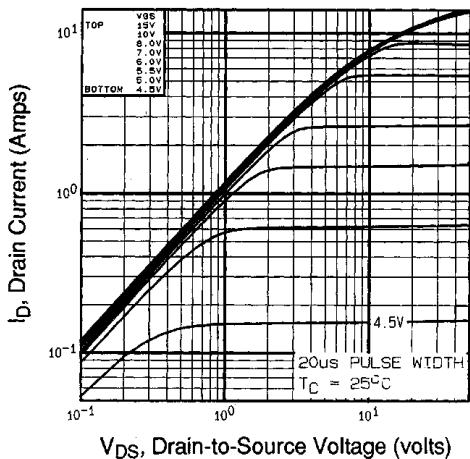
	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	250	—	—	V	$V_{GS}=0\text{V}$ , $I_D=250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.36	—	$\text{V}^\circ\text{C}$	Reference to $25^\circ\text{C}$ , $I_D=1\text{mA}$
$R_{\text{DS(on)}}$	Static Drain-to-Source On-Resistance	—	—	1.1	$\Omega$	$V_{GS}=10\text{V}$ , $I_D=2.6\text{A}$ ④
$V_{GS(\text{th})}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{DS}=V_{GS}$ , $I_D=250\mu\text{A}$
$g_f$	Forward Transconductance	1.5	—	—	S	$V_{DS}=50\text{V}$ , $I_D=2.6\text{A}$ ④
$I_{\text{DSS}}$	Drain-to-Source Leakage Current	—	—	25	$\mu\text{A}$	$V_{DS}=250\text{V}$ , $V_{GS}=0\text{V}$
		—	—	250		$V_{DS}=200\text{V}$ , $V_{GS}=0\text{V}$ , $T_J=125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS}=20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{GS}=-20\text{V}$
$Q_g$	Total Gate Charge	—	—	14	nC	$I_D=4.4\text{A}$
$Q_{gs}$	Gate-to-Source Charge	—	—	2.7		$V_{DS}=200\text{V}$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge	—	—	7.8		$V_{GS}=10\text{V}$ See Fig. 6 and 13 ④
$t_{d(on)}$	Turn-On Delay Time	—	7.0	—	ns	$V_{DD}=125\text{V}$
$t_r$	Rise Time	—	13	—		$I_D=4.4\text{A}$
$t_{d(off)}$	Turn-Off Delay Time	—	20	—		$R_G=18\Omega$
$t_f$	Fall Time	—	12	—		$R_D=28\Omega$ See Figure 10 ④
$L_D$	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6 mm (0.25in.) from package and center of die contact
$L_S$	Internal Source Inductance	—	7.5	—		
$C_{iss}$	Input Capacitance	—	260	—	pF	$V_{GS}=0\text{V}$
$C_{oss}$	Output Capacitance	—	77	—		$V_{DS}=25\text{V}$
$C_{rss}$	Reverse Transfer Capacitance	—	15	—		$f=1.0\text{MHz}$ See Figure 5

## Source-Drain Ratings and Characteristics

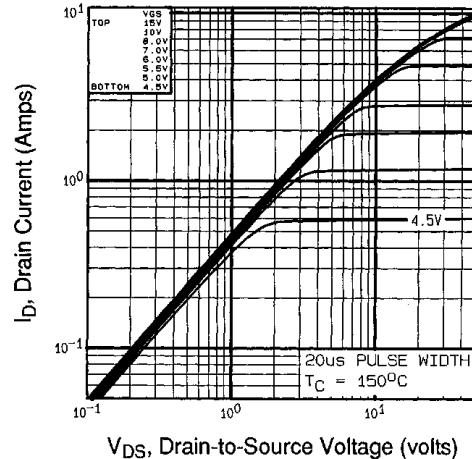
	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	4.4	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{SM}$	Pulsed Source Current (Body Diode) ①	—	—	14		
$V_{SD}$	Diode Forward Voltage	—	—	1.8	V	$T_J=25^\circ\text{C}$ , $I_S=4.4\text{A}$ , $V_{GS}=0\text{V}$ ④
$t_{rr}$	Reverse Recovery Time	—	200	400	ns	$T_J=25^\circ\text{C}$ , $I_F=4.4\text{A}$
$Q_{rr}$	Reverse Recovery Charge	—	0.93	1.9	$\mu\text{C}$	$dI/dt=100\text{A}/\mu\text{s}$ ④
$t_{on}$	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S+L_D$ )				

### Notes:

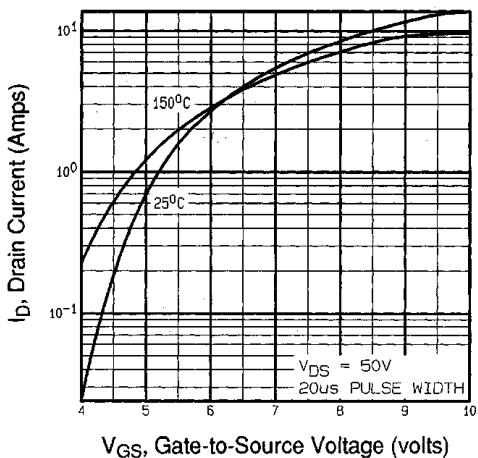
- ① Repetitive rating; pulse width limited by max. junction temperature (See Figure 11)
- ③  $I_{SD}\leq 4.4\text{A}$ ,  $di/dt\leq 90\text{A}/\mu\text{s}$ ,  $V_{DD}\leq V_{(\text{BR})\text{DSS}}$ ,  $T_J\leq 150^\circ\text{C}$
- ②  $V_{DD}=50\text{V}$ , starting  $T_J=25^\circ\text{C}$ ,  $L=8.3\text{mH}$ ,  $R_G=25\Omega$ ,  $I_{AS}=4.4\text{A}$  (See Figure 12)
- ④ Pulse width  $\leq 300\ \mu\text{s}$ ; duty cycle  $\leq 2\%$ .



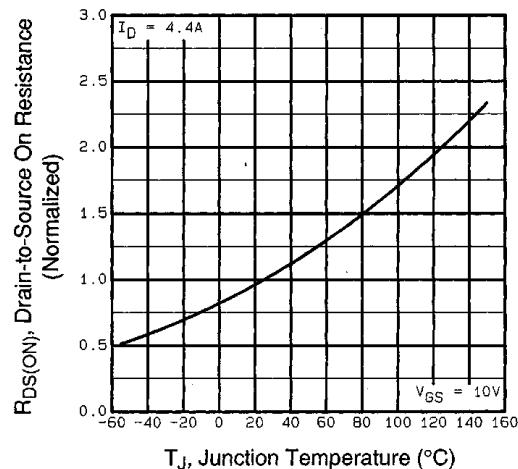
**Fig 1.** Typical Output Characteristics,  
 $T_C = 25^\circ\text{C}$



**Fig 2.** Typical Output Characteristics,  
 $T_C = 150^\circ\text{C}$



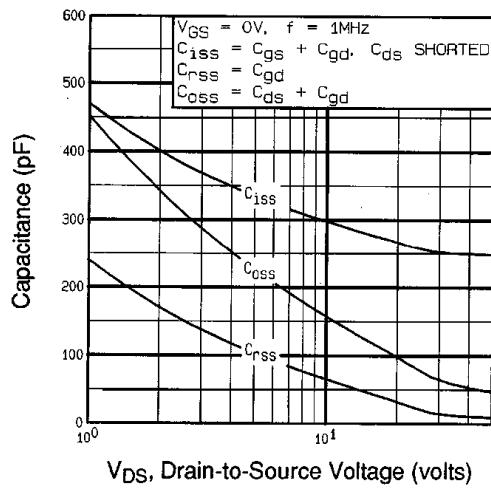
**Fig 3.** Typical Transfer Characteristics



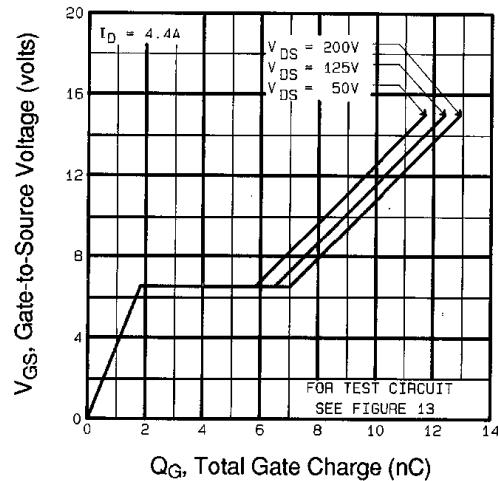
**Fig 4.** Normalized On-Resistance  
Vs. Temperature

# IRF624PbF

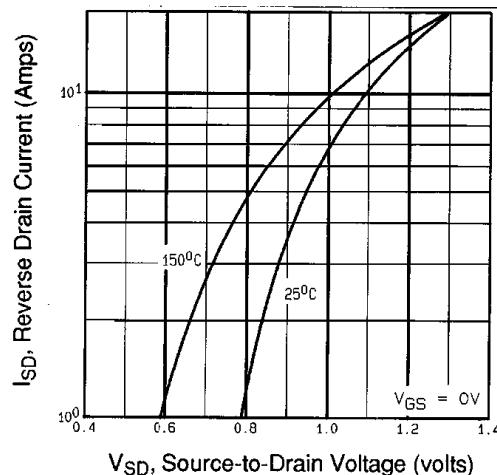
International  
**IR** Rectifier



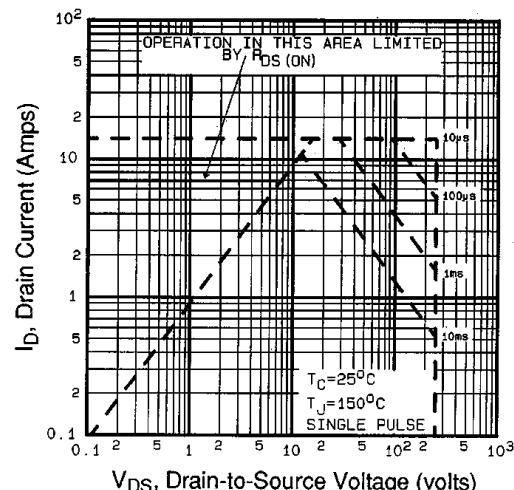
**Fig 5.** Typical Capacitance Vs.  
Drain-to-Source Voltage



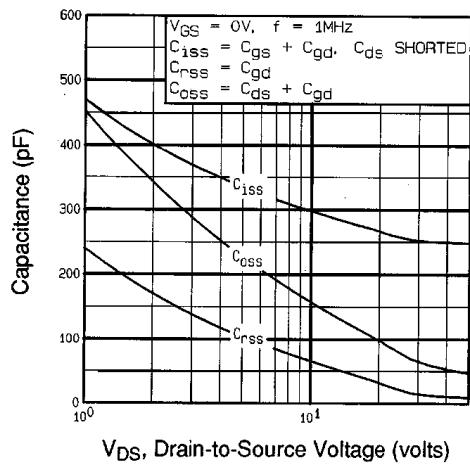
**Fig 6.** Typical Gate Charge Vs.  
Gate-to-Source Voltage



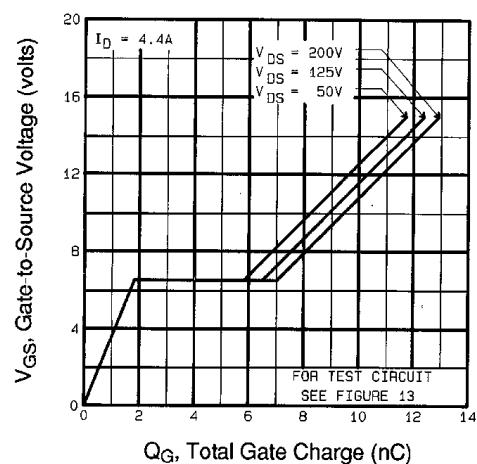
**Fig 7.** Typical Source-Drain Diode  
Forward Voltage



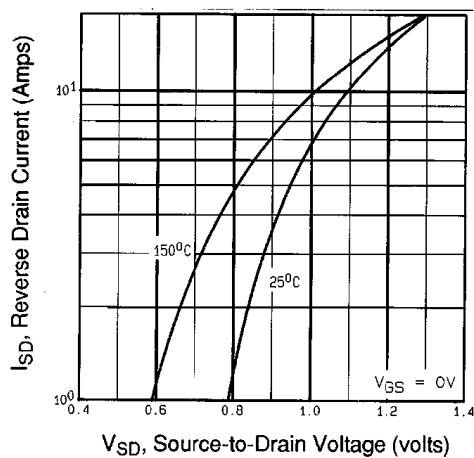
**Fig 8.** Maximum Safe Operating Area



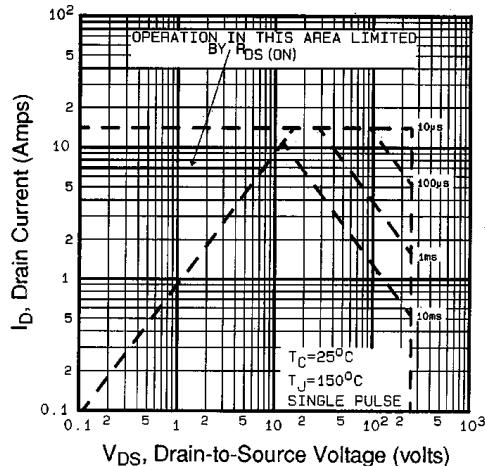
**Fig 5.** Typical Capacitance Vs.  
Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge Vs.  
Gate-to-Source Voltage



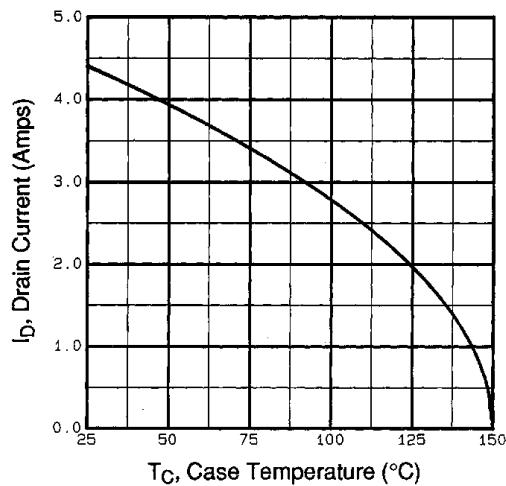
**Fig 7.** Typical Source-Drain Diode  
Forward Voltage



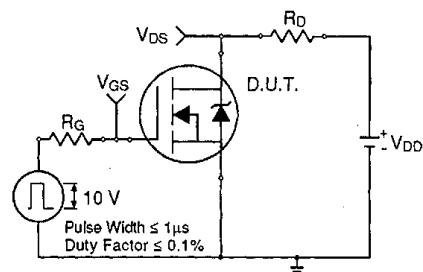
**Fig 8.** Maximum Safe Operating Area

# IRF624PbF

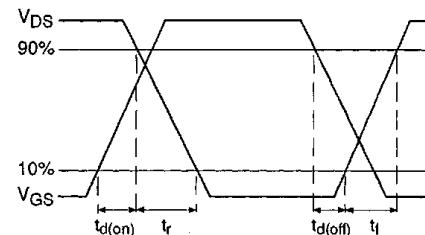
International  
**IR** Rectifier



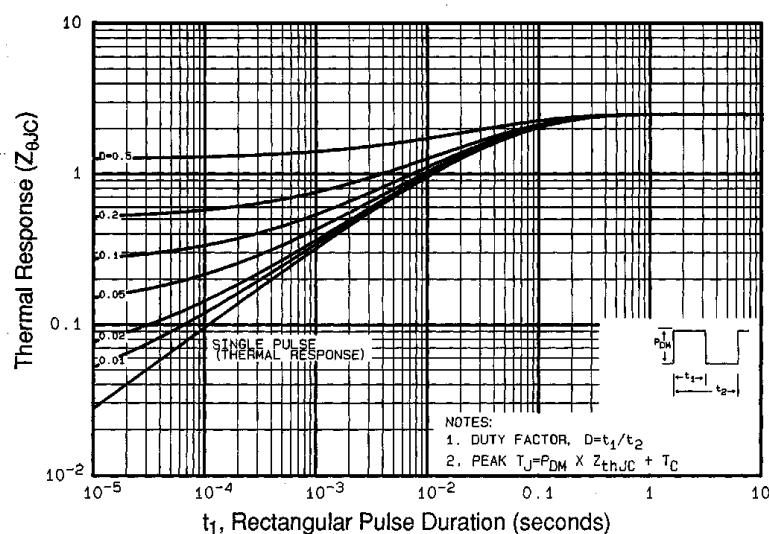
**Fig 9.** Maximum Drain Current Vs. Case Temperature



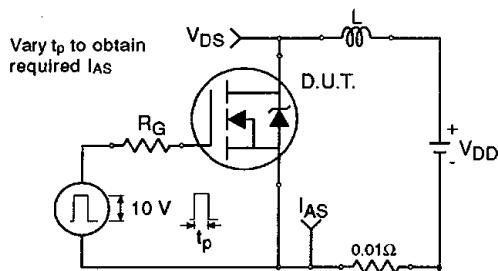
**Fig 10a.** Switching Time Test Circuit



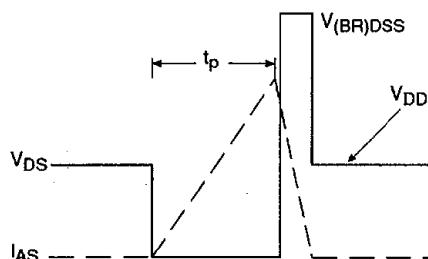
**Fig 10b.** Switching Time Waveforms



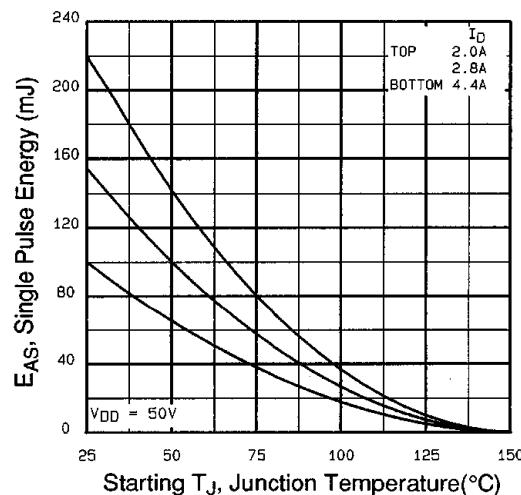
**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case



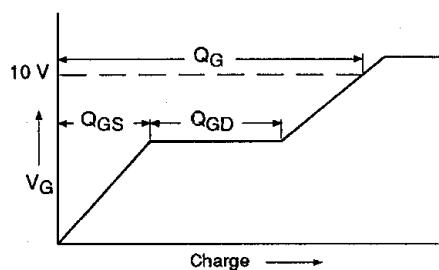
**Fig 12a.** Unclamped Inductive Test Circuit



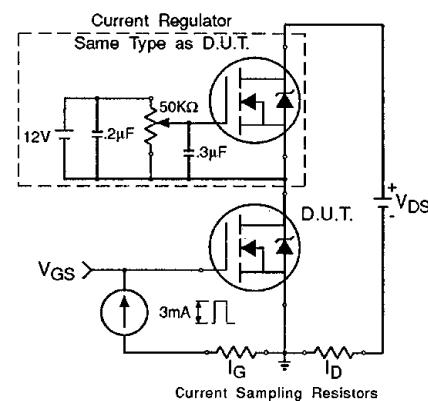
**Fig 12b.** Unclamped Inductive Waveforms



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current

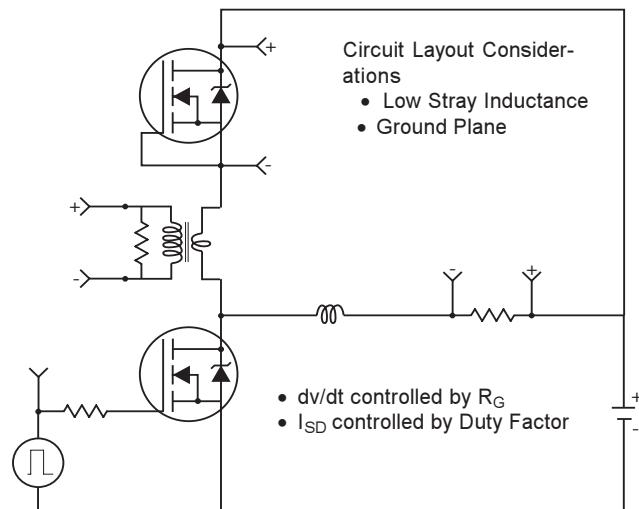


**Fig 13a.** Basic Gate Charge Waveform

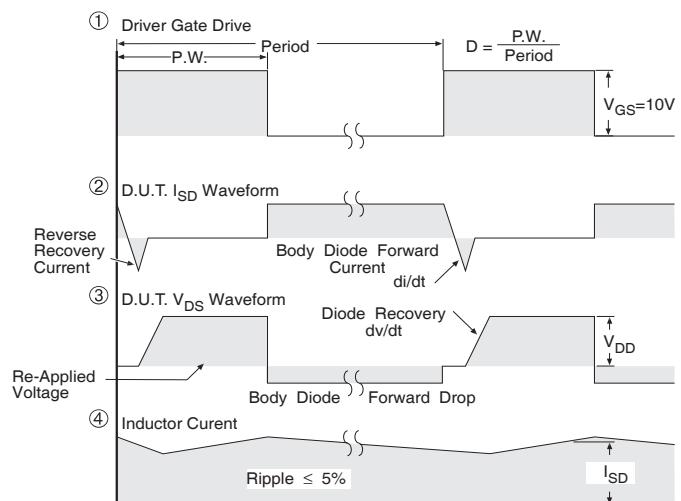


**Fig 13b.** Gate Charge Test Circuit

## Peak Diode Recovery dv/dt Test



\* Reverse Polarity for P-Channel

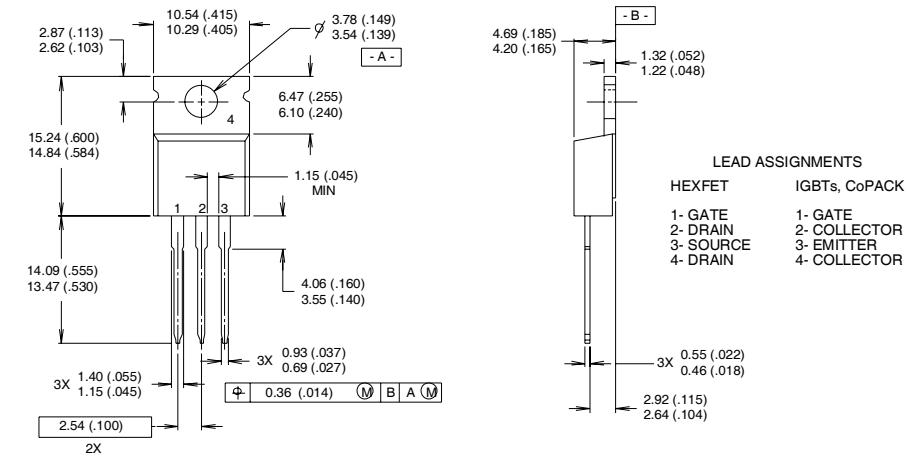


\*\*\*  $V_{GS} = 5.0V$  for Logic Level and 3V Drive Devices

**Fig. 14** For N and P Channel HEXFETS

## TO-220AB Package Outline

Dimensions are shown in millimeters (inches)



NOTES:

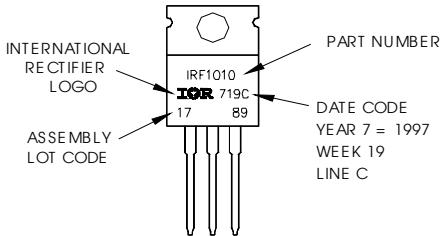
- 1 DIMENSIONING & TOLERANCING PER ANSI Y14.5M, 1982.
- 2 CONTROLLING DIMENSION : INCH

- 3 OUTLINE CONFORMS TO JEDEC OUTLINE TO-220AB.
- 4 HEATSINK & LEAD MEASUREMENTS DO NOT INCLUDE BURRS.

## TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010  
 LOT CODE 1789  
 ASSEMBLED ON WW 19, 1997  
 IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line position indicates "Lead-Free"



Data and specifications subject to change without notice.

International  
**IR** Rectifier

**IR WORLD HEADQUARTERS:** 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105

TAC Fax: (310) 252-7903

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